

<b>Notice of References Cited</b>	Application/Control No. 10/554,717		Applicant(s)/Patent Under Reexamination KUMAZAWA ET AL.	
	Examiner JEFFREY M. RUTKOWSKI		Art Unit 2619	Page 1 of 1

#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,473,599 A	12-1995	Li et al.	370/219
*	B	US-6,397,260 B1	05-2002	Wils et al.	709/238
*	C	US-2002/0186653 A1	12-2002	Jensen, Kell Michael	370/219
*	D	US-2003/0037165 A1	02-2003	Shinomiya, Daisuke	709/238
*	E	US-2003/0200333 A1	10-2003	Espieu et al.	709/240
*	F	US-2005/0025179 A1	02-2005	McLaggan et al.	370/468
*	G	US-6,931,452 B1	08-2005	Lamberton et al.	709/242
*	H	US-7,035,217 B1	04-2006	Vicisano et al.	370/236
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

#### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.